

<b>Notic of References Cited</b>	Application/Control No. 10/047,150	Applicant(s)/Patent Under Reexamination SCHOPPACH ET AL.	
	Examiner Joshua L Pritchett	Art Unit 2872	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,632,547	12-1986	Kaplan et al.	356/247
	B	US-6,061,175	05-2000	Watters, George M.	359/366
	C	US-6,355,206	03-2002	Hanzawa et al.	266/239
	D	US-5,138,484	08-1992	Schubert et al.	359/350
	E	US-6,404,547	06-2002	Hull, David A.	359/399
	F	US-5,579,333	11-1996	Neil et al.	372/99
	G	US-6,226,121	05-2001	Atkinson et al.	359/399
	H	US-6,160,867	12-2000	Murakami, Katsuhiko	378/84
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Harnisch, B.; Krunke, B.; Deyerler, M.; Bauereisen, S.; Papenburg, U. "Ultra-lightweight C/SiC Mirrors and Structures" August 1998, EESA			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.